



Patent Attorney's
Docket No. 032501-006

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of)
NGOI et al.) Group Art Unit: 2877
Application No.: 09/407,177) Examiner: Hwas Lee
Filed: September 28, 1999) Confirmation No.: 2405
For: HETERODYNE)
INTERFEROMETRY FOR SMALL)
SPACING MEASUREMENT)

AMENDMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

In response to the Office Action dated December 3, 2002, please amend the above-identified patent application as follows:

IN THE CLAIMS

Please substitute amended claim 16 as follows:

B1
16. (Twice Amended) A method for high speed and precision measurement of the distance between at least two near contact surfaces, one of which is an optically transparent element and the other is a substantially non-transparent element using heterodyne interferometry, comprising:

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